

## EAST Search History

| Ref # | Hits | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|--|---|------------------|---------|------------------|
| S13   | 2    | ("20040111231" or "20040128567") and (wafer die substrat\$3)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/08/18 15:00 |
| S14   | 1    | ("20040111231" or "20040128567") and (wafer die substrat\$3 chip) and (lot batch)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/08/18 13:04 |
| S15   | 420  | (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near3 (lot batch\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and (test\$3 verif\$7 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/08/18 16:04 |
| S16   | 316  | (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near3 (lot batch\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ( (test\$3 verif\$7 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and ( (determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2006/08/18 16:07 |

## EAST Search History

|     |     |  |   |    |    |                  |
|-----|-----|--|---|----|----|------------------|
| S17 | 12  | (test\$3 verif\$7 evaluat\$3 inspect\$3<br>analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc) with<br>(wafer near3 (lot batch\$2 lots<br>group\$3 pluralit\$3 multiple many<br>collection bundl\$3 bunch load heap<br>cluster\$3 multiplicit\$3 pack pile<br>plent\$3 collectiv\$3 numerous\$2))<br>and ( (test\$3 verif\$7 analy\$4<br>check\$3 valuat\$3 validat\$3<br>inspect\$3 investigat\$3 examin\$5<br>assess\$4 evaluat\$3 drc) same<br>(pluralit\$3 many multiple collection<br>multiplicit\$3 various different<br>chang\$3 plent\$3 collectiv\$3<br>numerous\$2 another several vary\$3<br>assort\$3 varied) near3 (voltage) )<br>and ( (determine\$5 find\$3 obtain\$3<br>evaluat\$3 calculat\$3 ascertain\$3<br>resolv\$3 decid\$3 choos\$3 select\$3)<br>with (operation\$3 near (voltage)) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/18 16:14 |
| S18 | 219 | (test\$3 verif\$7 evaluat\$3 inspect\$3<br>analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc) near4<br>(wafer near3 (lot batch\$2<br>simultaneous\$2 lots group\$3<br>pluralit\$3 multiple many collection<br>bundl\$3 bunch load heap cluster\$3<br>multiplicit\$3 pack pile plent\$3<br>collectiv\$3 numerous\$2)) and ( (test\$3 verif\$7 analy\$4 check\$3<br>valuat\$3 validat\$3 inspect\$3<br>investigat\$3 examin\$5 assess\$4<br>evaluat\$3 drc) same (pluralit\$3<br>many multiple collection<br>multiplicit\$3 various different<br>chang\$3 plent\$3 collectiv\$3<br>numerous\$2 another several vary\$3<br>assort\$3 varied) near3 (voltage) )<br>and ( (determine\$5 find\$3 obtain\$3<br>evaluat\$3 calculat\$3 ascertain\$3<br>resolv\$3 decid\$3 choos\$3 select\$3)<br>with (voltage) )    | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/18 16:21 |

## EAST Search History

|     |     |   |   |    |    |                  |
|-----|-----|---|---|----|----|------------------|
| S19 | 137 | (test\$3 verif\$7 evaluat\$3 inspect\$3<br>analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc) near4<br>(wafer near3 (lot batch\$2<br>simultaneous\$2 lots group\$3<br>pluralit\$3 multiple many collection<br>bundl\$3 bunch load heap cluster\$3<br>multiplicit\$3 pack pile plent\$3<br>collectiv\$3 numerous\$2)) and (<br>(test\$3 verif\$7 analy\$4 check\$3<br>valuat\$3 validat\$3 inspect\$3<br>investigat\$3 examin\$5 assess\$4<br>evaluat\$3 drc) with (pluralit\$3 many<br>multiple collection multiplicit\$3<br>various different chang\$3 plent\$3<br>collectiv\$3 numerous\$2 another<br>several vary\$3 assort\$3 varied)<br>near3 (voltage) ) and (<br>(determine\$5 find\$3 obtain\$3<br>evaluat\$3 calculat\$3 ascertain\$3<br>resolv\$3 decid\$3 choos\$3 select\$3)<br>with (voltage) )  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/18 16:23 |
| S20 | 10  | (test\$3 verif\$7 evaluat\$3 inspect\$3<br>analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc) near4<br>(wafer near3 (lot batch\$2<br>simultaneous\$2 lots group\$3<br>pluralit\$3 multiple many collection<br>bundl\$3 bunch load heap cluster\$3<br>multiplicit\$3 pack pile plent\$3<br>collectiv\$3 numerous\$2)) same (<br>(test\$3 verif\$7 analy\$4 check\$3<br>valuat\$3 validat\$3 inspect\$3<br>investigat\$3 examin\$5 assess\$4<br>evaluat\$3 drc) with (pluralit\$3 many<br>multiple collection multiplicit\$3<br>various different chang\$3 plent\$3<br>collectiv\$3 numerous\$2 another<br>several vary\$3 assort\$3 varied)<br>near3 (voltage) ) and (<br>(determine\$5 find\$3 obtain\$3<br>evaluat\$3 calculat\$3 ascertain\$3<br>resolv\$3 decid\$3 choos\$3 select\$3)<br>with (voltage) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 09:43 |

## EAST Search History

|     |     |  |   |    |    |                  |
|-----|-----|--|---|----|----|------------------|
| S21 | 172 | (test\$3 verif\$7 evaluat\$3 inspect\$3<br>analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc) near2<br>(wafer near3 (lot batch\$2<br>simultaneous\$2 lots group\$3<br>pluralit\$3 multiple many collection<br>bundl\$3 bunch load heap cluster\$3<br>multiplicit\$3 pack pile plent\$3<br>collectiv\$3 numerous\$2)) and (<br>(test\$3 verif\$7 analy\$4 check\$3<br>valuat\$3 validat\$3 inspect\$3<br>investigat\$3 examin\$5 assess\$4<br>evaluat\$3 drc) same (pluralit\$3<br>many multiple collection<br>multiplicit\$3 various different<br>chang\$3 plent\$3 collectiv\$3<br>numerous\$2 another several vary\$3<br>assort\$3 varied) near3 (voltage) )<br>and ( (determine\$5 find\$3 obtain\$3<br>evaluat\$3 calculat\$3 ascertain\$3<br>resolv\$3 decid\$3 choos\$3 select\$3)<br>with (voltage) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 10:03 |
| S22 | 10  | (test\$3 verif\$7 evaluat\$3 inspect\$3<br>analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc) near<br>(wafer near3 (lot batch\$2<br>simultaneous\$2 lots group\$3<br>pluralit\$3 multiple many collection<br>bundl\$3 bunch load heap cluster\$3<br>multiplicit\$3 pack pile plent\$3<br>collectiv\$3 numerous\$2)) same (<br>(test\$3 verif\$7 analy\$4 check\$3<br>valuat\$3 validat\$3 inspect\$3<br>investigat\$3 examin\$5 assess\$4<br>evaluat\$3 drc) same (pluralit\$3<br>many multiple collection<br>multiplicit\$3 various different<br>chang\$3 plent\$3 collectiv\$3<br>numerous\$2 another several vary\$3<br>assort\$3 varied) near3 (voltage) )<br>and ( (determine\$5 find\$3 obtain\$3<br>evaluat\$3 calculat\$3 ascertain\$3<br>resolv\$3 decid\$3 choos\$3 select\$3)<br>with (voltage) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 10:08 |
| S23 | 1   | "20050172182" and (relativ\$2 near<br>significance)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 10:39 |

## EAST Search History

|     |     |   |   |    |    |                  |
|-----|-----|---|---|----|----|------------------|
| S24 | 60  | (test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafter prob\$3) same ( (test\$3 verif\$7 analy\$4 simulat\$3 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and (wafer near2 (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 10:56 |
| S25 | 7   | (test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafter prob\$3) same ( (test\$3 verif\$7 analy\$4 simulat\$3 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and (wafers near2 compar\$3)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 11:00 |
| S26 | 140 | (test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with wafer with ( (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near2 (voltage) )  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 11:03 |
| S27 | 112 | S26 and @ad<"20040115"  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 11:12 |

## EAST Search History

|     |      |   |   |    |    |                  |
|-----|------|---|---|----|----|------------------|
| S28 | 1    | (test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near (lot lots batch\$2 collection set)) with ( (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near2 (voltage) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 11:04 |
| S29 | 3690 | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) )   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 11:14 |
| S30 | 1939 | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) NEAR3 (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) )  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 11:14 |
| S31 | 871  | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) NEAR (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) )   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:23 |

## EAST Search History

|     |     |   |   |    |    |                  |
|-----|-----|---|---|----|----|------------------|
| S32 | 168 | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 simulat\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) ) and ( (test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) )   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:26 |
| S33 | 43  | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 simulat\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) ) and ( (test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and ( (optimum optimal ideal favorable best nominal) with (voltag\$2) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:33 |
| S34 | 28  | S33 and @ad<"20040115"  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:28 |

## EAST Search History

|     |          |  |   |    |    |                  |
|-----|----------|--|---|----|----|------------------|
| S35 | 24       | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 simulat\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) ) and ( (test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and ( (optimum optimal ideal favorable best nominal) near3 (voltag\$2) ) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:34 |
| S36 | 25209373 | @ad<"20040115"   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:35 |
| S37 | 17       | S35 and S36  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 12:35 |
| S38 | 5        | (US-20040128567-\$ or US-20050050172-\$ or US-20030056029-\$).did. or (US-6414508-\$ or US-5457695-\$). did.   | US-PGPUB;<br>USPAT  | OR | ON | 2006/08/19 12:42 |
| S39 | 10       | ("5519333"   "5521524"   "5742177"   "5889408"   "6140832"   "6147316"   "6175244"   "6175812"   "6230293").PN. OR ("6414508"). URPN.  | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 12:55 |



## EAST Search History

|     |    |  |                              |    |    |                  |
|-----|----|--|------------------------------|----|----|------------------|
| S40 | 10 | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) near4 (test\$3 verif\$7 simulat\$3 reliabilit\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) ) and ( (test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and ( (determine\$5 find\$3 obtain\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage\$2) with (optimal optimum nominal favorable best ideal) ) | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:04 |
| S41 | 8  | ( (wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) near4 (test\$3 verif\$7 simulat\$3 reliabilit\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) ) same ( (determine\$5 find\$3 obtain\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage\$2) with (optimal optimum nominal favorable best ideal) )  | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:18 |

## EAST Search History

|     |    |  |                              |    |    |                  |
|-----|----|--|------------------------------|----|----|------------------|
| S42 | 26 | (wafer near5 (test\$3 verif\$7<br>evaluat\$3 inspect\$3 simulat\$3<br>sort\$3 analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc)) and<br>((pluralit\$3 many multiple collection<br>multiplicit\$3 various different<br>chang\$3 plent\$3 collectiv\$3<br>numerous\$2 another several vary\$3<br>assort\$3 varied) near5 (voltag\$2) )<br>and ((determine\$5 find\$3 obtain\$3<br>second evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(voltag\$2) near3 (optimal optimum<br>nominal favorable best ideal) ) and (<br>(determine\$5 find\$3 obtain\$3<br>detect\$3 evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(failur\$3 error\$3 deficienc\$3 fault<br>glitch\$2) ) and ( (wafer with (lot<br>batch\$2 sets lots pluralit\$3 multiple<br>many collection bundl\$3 bunch load<br>heap cluster\$3 multiplicit\$3 pack<br>pile plent\$3 collectiv\$3<br>numerous\$2) ) ) | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:21 |
| S43 | 13 | S42 and S36  | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:26 |

## EAST Search History

|     |    |  |                              |    |    |                  |
|-----|----|--|------------------------------|----|----|------------------|
| S44 | 13 | (wafer near5 (test\$3 verif\$7<br>reliabilit\$3 evaluat\$3 inspect\$3<br>simulat\$3 sort\$3 analy\$4 check\$3<br>validat\$3 investigat\$3 examin\$5<br>drc)) and ((pluralit\$3 many multiple<br>collection multiplicit\$3 various<br>different chang\$3 plent\$3<br>collectiv\$3 numerous\$2 another<br>several vary\$3 assort\$3 varied)<br>near5 (voltag\$2) ) and<br>((determine\$5 find\$3 obtain\$3<br>second evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(voltag\$2) near3 (optimal optimum<br>nominal favorable best ideal) ) and ( (determine\$5 find\$3 obtain\$3<br>detect\$3 evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(failur\$3 error\$3 deficienc\$3 fault<br>glitch\$2) ) and ( (wafer with (lot<br>batch\$2 sets lots pluralit\$3 multiple<br>many collection bundl\$3 bunch load<br>heap cluster\$3 multiplicit\$3 pack<br>pile plent\$3 collectiv\$3<br>numerous\$2) ) ) and<br>@ad<"20040115" | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:30 |
|-----|----|--|------------------------------|----|----|------------------|

## EAST Search History

|     |    |  |                              |    |    |                  |
|-----|----|--|------------------------------|----|----|------------------|
| S45 | 4  | (wafer near5 (test\$3 verif\$7<br>reliabilit\$3 evaluat\$3 inspect\$3<br>simulat\$3 sort\$3 analy\$4 check\$3<br>validat\$3 investigat\$3 examin\$5<br>drc)) and ((pluralit\$3 many multiple<br>collection multiplici\$3 various<br>different chang\$3 plent\$3<br>collectiv\$3 numerous\$2 another<br>several vary\$3 assort\$3 varied)<br>near5 (voltag\$2) ) and<br>((determine\$5 find\$3 obtain\$3<br>second evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(voltag\$2) near3 (optimal optimum<br>favorable best ideal) ) and ( (determine\$5 find\$3 obtain\$3<br>detect\$3 evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(failur\$3 error\$3 deficienc\$3 fault<br>glitch\$2) ) and ( (wafer with (lot<br>batch\$2 sets lots pluralit\$3 multiple<br>many collection bundl\$3 bunch load<br>heap cluster\$3 multiplici\$3 pack<br>pile plent\$3 collectiv\$3<br>numerous\$2) ) ) and<br>@ad<"20040115" | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:31 |
| S46 | 72 | ((determine\$5 find\$3 obtain\$3<br>second evaluat\$3 identif\$7<br>calculat\$3 ascertain\$3 resolv\$3<br>decid\$3 choos\$3 select\$3) with<br>(voltag\$2) near3 (optimal optimum<br>favorable best ideal) ) and (wafer<br>near5 (test\$3 verif\$7 reliabilit\$3<br>evaluat\$3 inspect\$3 simulat\$3<br>sort\$3 analy\$4 check\$3 validat\$3<br>investigat\$3 examin\$5 drc)) and<br>@ad<"20040115"  | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:32 |

## EAST Search History

|     |     |   |                              |    |    |                  |
|-----|-----|---|------------------------------|----|----|------------------|
| S47 | 48  | ((determine\$5 find\$3 obtain\$3 second evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage\$2) near3 (optimal optimum favorable best ideal) ) and (wafer near5 (test\$3 verif\$7 reliabilit\$3 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and @ad<"20040115" and ( (wafer with (lot batch\$2 sets lots pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2) ) )   | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:43 |
| S48 | 4   | (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near (wafer near3 (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ( (test\$3 verif\$7 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage) ) and ( (determine\$5 find\$3 obtain\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage) with (optimal favorable best ideal) ) | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:51 |
| S49 | 113 | test\$3 with wafer with (various varying vary varied different\$2 chang\$3 another) with voltage  | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:53 |
| S50 | 87  | S49 and S36   | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 13:58 |
| S51 | 55  | (wafer near2 (lots lot batch\$2)) with electrical with test\$3 and S36  | US-PGPUB;<br>USPAT;<br>USOCR | OR | ON | 2006/08/19 14:06 |

## EAST Search History

|     |    |  |   |    |    |                  |
|-----|----|--|---|----|----|------------------|
| S52 | 13 | S51 and Voltag\$2 with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied various) | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 14:09 |
| S53 | 1  | "6414508".pn.  | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 14:05 |
| S54 | 1  | "6414508".pn. and voltage  | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 14:05 |
| S55 | 91 | (wafer near2 (lots lot batch\$2)) with sort\$3 and S36   | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 14:06 |
| S56 | 8  | S55 and Voltag\$2 with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied various) | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 14:17 |
| S57 | 1  | "20040128567" and (wafer)  | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR | ON | 2006/08/19 14:18 |
| S58 | 1  | "20040111231" and opti\$5  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 15:21 |
| S59 | 1  | "20040111231" and (Fail\$4 error\$3)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2006/08/19 15:22 |